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# N-Channel PowerTrench MOSFET 25 V, 30 A, 8.5 m $\Omega$

#### **Features**

- Max  $r_{DS(on)}$  = 8.5 m $\Omega$  at  $V_{GS}$  = 10 V,  $I_D$  = 16.5 A
- Max  $r_{DS(on)}$  = 12.5 m $\Omega$  at  $V_{GS}$  = 4.5 V,  $I_D$  = 13.0 A
- 100% UIL test
- RoHS Compliant

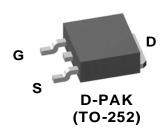
### **General Description**

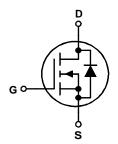
This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for low gate charge, low  $r_{\mbox{\footnotesize{DS(on)}}}$  and fast switching speed.

### **Applications**

- Vcore DC-DC for Desktop Computers and Servers
- VRM for Intermediate Bus Architecture







#### **MOSFET Maximum Ratings** T<sub>C</sub> = 25 °C unless otherwise noted

Symbol	Parameter			Ratings	Units	
V <sub>DS</sub>	Drain to Source Voltage			25	V	
V <sub>GS</sub>	Gate to Source Voltage			±20	V	
	Drain Current -Continuous (Package limited)	T <sub>C</sub> = 25 °C		30		
	-Continuous (Silicon limited)	T <sub>C</sub> = 25 °C		49	^	
<sup>I</sup> D	-Continuous	T <sub>A</sub> = 25 °C	(Note 1a)	16.5	A	
	-Pulsed			70		
E <sub>AS</sub>	Single Pulse Avalanche Energy		(Note 3)	40	mJ	
$P_{D}$	Power Dissipation	T <sub>C</sub> = 25 °C		33	W	
	Power Dissipation	T <sub>A</sub> = 25 °C	(Note 1a)	3.7	VV	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature R	ange		-55 to +175	°C	

#### **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction to Case	4.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a	40	*C/VV

## **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
ÁTVFI€HŒ	ÁTVFI€HŒ	ÁÁÁÁD-PAK (TO-252)ÁÁÁÁ	<b>₩₩₩₩</b> 3 " <b>/₩₩₩₩</b>		₩₩£2500 units

## **Electrical Characteristics** $T_J = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units		
Off Characteristics								
$BV_{DSS}$	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	25			V		
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, referenced to 25 °C		7.5		mV/°C		
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 20 V, V <sub>GS</sub> = 0 V			1	μΑ		
$I_{GSS}$	Gate to Source Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$			±100	nA		

#### On Characteristics

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	1.0	1.8	3.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250 \mu A$ , referenced to 25 °C		-6.3		mV/°C
r <sub>DS(on)</sub>	Static Drain to Source On Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 16.5 A		7.0	8.5	
		V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 13.0 A		9.9	12.5	mΩ
		$V_{GS} = 10 \text{ V}, I_D = 16.5 \text{ A}, T_J = 150 ^{\circ}\text{C}$		10.4	12.7	
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 5 V, I <sub>D</sub> = 16.5 A		81		S

#### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 40.V V 0.V	1195	1590	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 13 \text{ V}, V_{GS} = 0 \text{ V},$ $f = 1 \text{ MHz}$	225	295	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 = 1 IVITIZ	200	300	pF
$R_g$	Gate Resistance		0.7	1.4	Ω

## **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time		8	16	ns
t <sub>r</sub>	Rise Time	V <sub>DD</sub> = 13 V, I <sub>D</sub> = 16.5 A,	5	10	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS}$ = 10 V, $R_{GEN}$ = 6 $\Omega$	19	34	ns
t <sub>f</sub>	Fall Time		3	10	ns
$Q_g$	Total Gate Charge	V <sub>GS</sub> = 0 V to 10 V	20	29	nC
Qg	Total Gate Charge	$V_{GS} = 0 \text{ V to } 4.5 \text{ V}$ $V_{DD} = 13 \text{ V}$	11	15	nC
Q <sub>gs</sub>	Gate to Source Charge	I <sub>D</sub> = 16.5 A	3.3		nC
$Q_{gd}$	Gate to Drain "Miller" Charge		4.2		nC

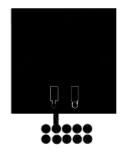
#### **Drain-Source Diode Characteristics**

V <sub>SD</sub>	Source to Drain Dioge Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 3.1 A (Note 2)	0.8	1.2	V
		V <sub>GS</sub> = 0 V, I <sub>S</sub> = 16.5 A (Note 2)	0.9	1.3	
t <sub>rr</sub>	Reverse Recovery Time	I <sub>F</sub> = 16.5 A, di/dt = 100 A/μs	13	22	ns
Q <sub>rr</sub>	Reverse Recovery Charge	T <sub>F</sub> = 16.5 A, α//αι = 100 A/μs	3	10	nC

#### Notes:

<sup>1:</sup> R<sub>0,IA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.

R<sub>0,IC</sub> is guaranteed by design while R<sub>0,IA</sub> is determined by the user's board design.



 a) 40 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper



b) 96 °C/W when mounted on a minimum pad

- 2: Pulse Test: Pulse Width < 300  $\mu$ s, Duty cycle < 2.0%.
- 3:  $E_{AS}$  of 40 mJ is based on starting  $T_J = 25$  °C, L = 1 mH,  $I_{AS} = 9$  A,  $V_{DD} = 23$  V,  $V_{GS} = 10$  V. 100% test at L = 0.1 mH,  $I_{AS} = 20$  A.

## **Typical Characteristics** $T_J = 25$ °C unless otherwise noted

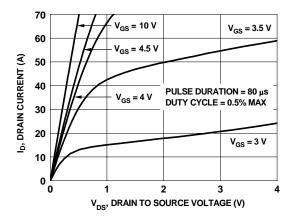


Figure 1. On Region Characteristics

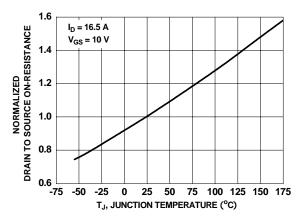


Figure 3. Normalized On Resistance vs Junction Temperature

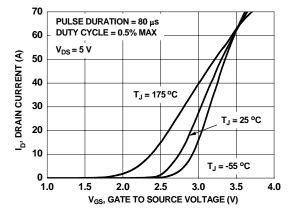


Figure 5. Transfer Characteristics

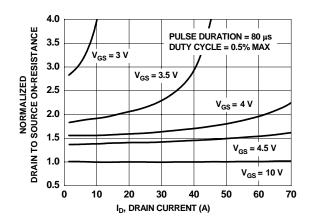


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

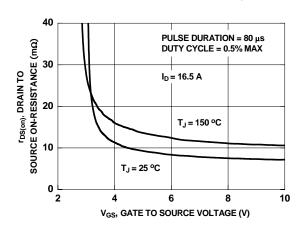


Figure 4. On-Resistance vs Gate to Source Voltage

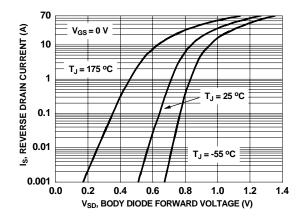


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

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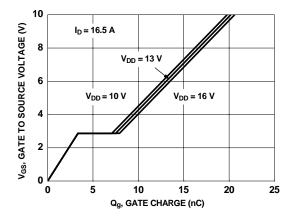


Figure 7. Gate Charge Characteristics

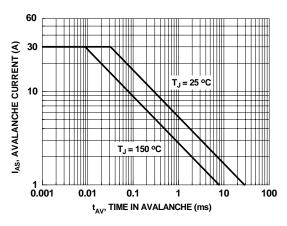


Figure 9. Unclamped Inductive Switching Capability

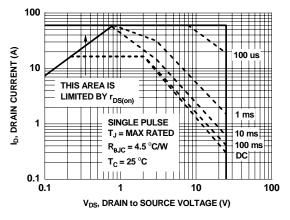


Figure 11. Forward Bias Safe Operating Area

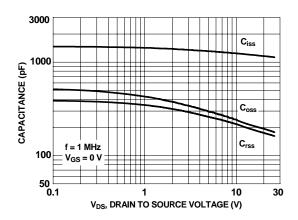


Figure 8. Capacitance vs Drain to Source Voltage

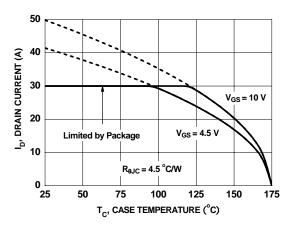


Figure 10. Maximum Continuous Drain Current vs Case Temperature

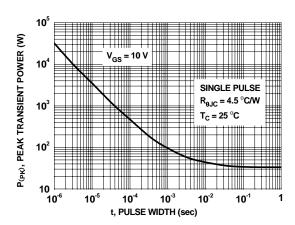


Figure 12. Single Pulse Maximum Power Dissipation

## **Typical Characteristics** $T_J = 25$ °C unless otherwise noted

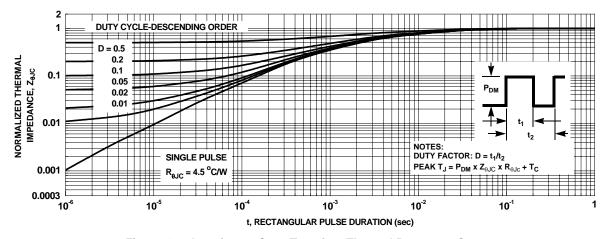


Figure 13. Junction-to-Case Transient Thermal Response Curve

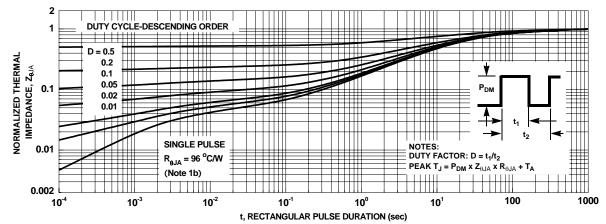


Figure 14. Junction-to-Ambient Transient Thermal Response Curve

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